



PTO/SB/08a/b (08-03)

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<p>Substitute for form 1449A/B/PTO</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p><i>(Use as many sheets as necessary)</i></p>				Complete if Known	
				Application Number	10/759,079-Conf. #7174
				Filing Date	January 20, 2004
				First Named Inventor	Kie Y. Ahn
				Art Unit	2818
				Examiner Name	D. Nhu
Sheet	1	of	1	Attorney Docket Number	M4065.0383/P383-C

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
**AA		6,259,407	07/10/2001	Tran	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS					
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Examiner Signature	<i>D. Nhu</i>	Date Considered	5/12/05
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Substitute for form 1448A/B/PTO

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet

1

of

1

Complete if Known

Application Number	NOT YET ASSIGNED 10/759,079
Filing Date	January 20, 2004
First Named Inventor	Kie Y. Ahn
Art Unit	N/A
Examiner Name	Not Yet Assigned

Attorney Docket Number M4065.0383/P383-C

U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
AA	5,429,978	07-04-1995	Lu et al.*		
AB	4,575,700	03-1986	Dalman*		
AC	5,426,399	08-1995	Matsubayashi et al.*		
AD	5,447,887	09-05-1995	Filipiak et al.*		
AE	5,849,625	12-15-1998	Hsue, et al.*		
AF	6,140,688	10-31-2000	Gardner et al.*		
AG	6,255,698	07-03-2001	Gardner et al.*		

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Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CA	"Silicon Micromachined Waveguides for Millimeter-Wave and Submillimeter-Wave Frequencies" by William R. McGarth, Christopher Walker, Markus Yap, and Yu-Chong Tai, IEE Microwave and Guided Wave Letters, Vol. 3, No. 3, March 1993, Pages 61-63.*		
CB	"Si and SiGe Millimeter-Wave Integrated Circuits" by Peter Russer, IEE Transactions on Microwave Theory and Techniques, Vol. 46, No. 5, May 1998, Pages 590-603*		
CC	Spigel et al., "Impact of Light Illumination and Passivation Layer on Silicon Finite Ground Coplanar Waveguide Transmission Line Properties", October 2000, IEE Transaction on Microwave Theory and Techniques, Volume 48, No. 10, pages 1673-1679.*		
CD	Yang et al., "Characteristics of Trenched Coplanar Waveguide for High Resistivity Si MMIC Applications", May 1998, IEE Transaction on Microwave Theory and Techniques, Volume 46, No. 5, pages 623-631.*		
CE	Hu et al., "Characteristics of Trenched Coplanar Waveguide for Si MMIC Applications", June 1997, IEE MTT-Digest, pages 735-738.*		

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Examiner Signature		Date Considered	10/14/04
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